

Title (en)

LINE PROFILE ASYMMETRY MEASUREMENT

Title (de)

LINIENPROFIL-ASYMMETRIEMESSUNG

Title (fr)

MESURE D'ASYMETRIE DE PROFIL LINEAIRE

Publication

EP 1678466 A2 20060712 (EN)

Application

EP 04784089 A 20040913

Priority

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Abstract (en)

[origin: WO2005028992A2] This disclosure provides methods for measuring asymmetry of features, such as lines of a diffraction grating. On implementation provides a method of measuring asymmetries in microelectronic devices by directing light at an array of microelectronic features of a microelectronic device. The light illuminates a portion of the array that encompasses the entire length and width of a plurality of the microelectronic features. Light scattered back from the array is detected. One or more characteristics of the back-scattered light may be examined by examining data from complementary angles of reflection. This can be particularly useful for arrays of small periodic structures for which standard modeling techniques would be impractically complex or take inordinate time.

IPC 1-7

G01B 11/02

IPC 8 full level

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IPC 8 main group level

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CPC (source: EP KR)

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